

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 21.0003
CB Certificate No.: 50600408 ITL

Schedule Number: IECQ-L ULTW 21.0003-S Rev No.: 2 Revision Date: 2022/06/19 Page 1 of 3

Appendix-1 (50600408 ITL) Schedule of Scope to Certificate of Approval

Test Technology 測試項目	Test Method 測試標準
Electrostatic Discharge (ESD) Test - Human Body Model (HBM) 人体模型静电敏感度试验	ANSI/ESDA/JEDEC JS-001 AEC-Q100-002 MIL-STD-883L-2017 method 3015.9 AEC-Q101-001 -REV-A 2005 GJB 548B-2005 方法 3015
Electrostatic Discharge (ESD) Test - Charged Device Model (CDM) 充电器件模型静电敏感度试验	ANSI/ESDA/JEDEC JS-002 AEC-Q100-011 AEC-Q101-005 July 18 2005
IC Latch-Up Test 集成电路闩锁测试	JEDEC JESD78F-2022
Temperature, Bias, And Operating Life (HTOL, LTOL, HTGB, HTRB)) 温度 偏压 寿命试验	JEDEC JESD22-A108 AEC Q100-005
Steady-State Temperature-Humidity Bias Life Test (THB) 恒定温湿度偏压寿命试验	JEDEC JESD22-A101
Highly Accelerated Temperature and Humidity Stress Test (HAST) 高加速温湿度应力试验	JEDEC JESD22-A110
High Temperature Storage Life (HTSL) 高温存储寿命试验	JEDEC JESD22-A103
Temperature Cycling (TC) 温度循环试验	JEDEC JESD22-A104
Accelerated Moisture Resistance - Unbiased Autoclave (PCT) 高压蒸煮试验	JEDEC JESD22-A102
Low Temperature Storage Life (LTSL) 低温存储寿命试验	JEDEC JESD22-A119

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Test Technology 測試項目	Test Method 測試標準
Power and Temperature Cycling (PTC) 功率和温度循环	JEDEC JESD22-A105
Early Life Failure Rate (ELFR) 早夭测试	AEC Q100-008 , JEDEC JESD22-A108
Preconditioning of Nonhermetic Surface Mount Devices Prior to Reliability Testing (Pre-con) 非密封表面贴装器件可靠性测试前的预处理	JEDEC JESD22-A113 , JEDEC J-STD-020
3D Optical Microscope (3D OM) 3 维数字光学显微镜	JF-WI-141
X-RAY microscope X-射线	JF-WI-023
Scanning Acoustic Tomography (SAT) 超音波扫描	JF-WI-025
Laser 镭射	JF-WI-007
InGaAs microscope 砷化镓微光显微镜	JF-WI-038
Optical Beam Induced Resistance Change (OBIRCH) 镭射加热扫描定位	JF-WI-097
Thermal 热影像分析仪	JF-WI-040
IV cure tracer 曲线追踪仪测试	JF-WI-029
Probe 射频探针	JF-WI-030
Reactive-Ion Etching RIE 气体蚀刻	JF-WI-098

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Test Technology 測試項目	Test Method 測試標準
Grinder 研磨	JF-WI-146
Secondary Electron Microscope (SEM) 扫描电镜-8100	JF-WI-026
Secondary Electron Microscope (SEM) 扫描电镜-Apreo2C	JF-WI-039
Dual Beam Focused Ion beam (Dual Beam FIB) 双束离子束 (G4)	JF-WI-027
Focused Ion beam (FIB) 聚焦离子束- Helios 5	JF-WI-136
Focused Ion beam (FIB) 聚焦离子束线路修补-CKT	JF-WI-094
Transmission electron microscope (TEM) 透射电镜-Talos F200i	JF-WI-135

Technical Reviewer of DQS: Wichael Chou Date: 6/19/2022

